

**Search Notes**

Application/Control No.

10/671,366

Examiner

Vincent Lai

Applicant(s)/Patent under  
Reexamination

LUDDEN ET AL.

Art Unit

2181

**SEARCHED**

Class	Subclass	Date	Examiner
712	239	8/12/2006	VL
712	235	8/12/2006	VL
712	233	8/12/2006	VL
712	234	8/12/2006	VL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search terms: level bias, branch prediction, mask, test, simultion, vector	8/14/2006	VL